

## SMPS MOSFET

**IRF3000**

HEXFET® Power MOSFET

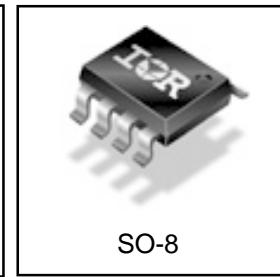
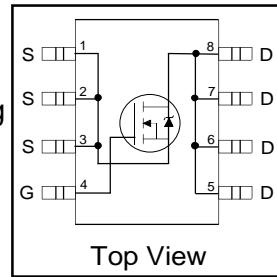
### Applications

- High frequency DC-DC converters

V <sub>DSS</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>
300V	0.40Ω@V <sub>GS</sub> = 10V	1.6A

### Benefits

- Low Gate to Drain Charge to Reduce Switching Losses
- Fully Characterized Capacitance Including Effective C<sub>OSS</sub> to Simplify Design, (See App. Note AN1001)
- Fully Characterized Avalanche Voltage and Current



### Absolute Maximum Ratings

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>A</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	1.6	A
I <sub>D</sub> @ T <sub>A</sub> = 70°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	1.3	
I <sub>DM</sub>	Pulsed Drain Current ①	13	
P <sub>D</sub> @ T <sub>A</sub> = 25°C	Power Dissipation④	2.5	W
	Linear Derating Factor	0.02	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	± 30	V
dv/dt	Peak Diode Recovery dv/dt ⑥	8.9	V/ns
T <sub>J</sub>	Operating Junction and	-55 to + 150	°C
T <sub>STG</sub>	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	

### Thermal Resistance

Symbol	Parameter	Typ.	Max.	Units
R <sub>θJL</sub>	Junction-to-Drain Lead	—	20	°C/W
R <sub>θJA</sub>	Junction-to-Ambient ④	—	50	

Notes ① through ⑥ are on page 8

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# IRF3000

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## Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	300	—	—	V	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	—	0.38	—	$\text{V}/^\circ\text{C}$	Reference to $25^\circ\text{C}$ , $I_D = 1\text{mA}$ ③
$R_{\text{DS}(\text{on})}$	Static Drain-to-Source On-Resistance	—	0.34	0.40	$\Omega$	$V_{\text{GS}} = 10\text{V}, I_D = 0.96\text{A}$ ③
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	3.0	—	5.0	V	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$
$I_{\text{DSS}}$	Drain-to-Source Leakage Current	—	—	25	$\mu\text{A}$	$V_{\text{DS}} = 300\text{V}, V_{\text{GS}} = 0\text{V}$
		—	—	250		$V_{\text{DS}} = 240\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 150^\circ\text{C}$
$I_{\text{GSS}}$	Gate-to-Source Forward Leakage	—	—	100	$\text{nA}$	$V_{\text{GS}} = 30\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{\text{GS}} = -30\text{V}$

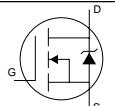
## Dynamic @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

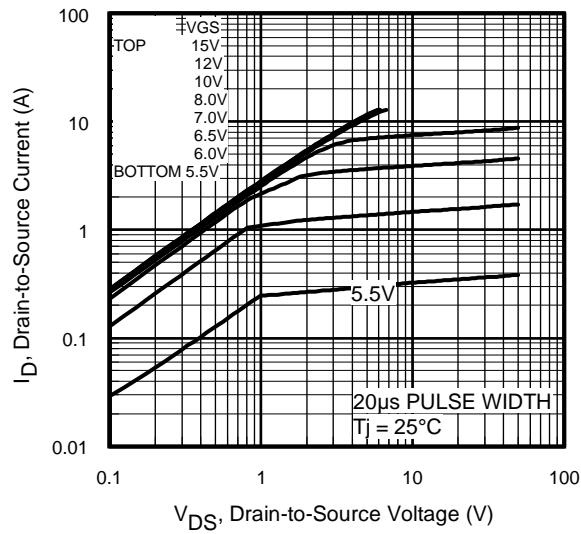
	Parameter	Min.	Typ.	Max.	Units	Conditions
$g_{\text{fs}}$	Forward Transconductance	2.0	—	—	S	$V_{\text{DS}} = 50\text{V}, I_D = 0.96\text{A}$
$Q_g$	Total Gate Charge	—	22	33	nC	$I_D = 0.96\text{A}$
$Q_{\text{gs}}$	Gate-to-Source Charge	—	4.7	7.1		$V_{\text{DS}} = 240\text{V}$
$Q_{\text{gd}}$	Gate-to-Drain ("Miller") Charge	—	11	17		$V_{\text{GS}} = 10\text{V},$
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	8.2	—		$V_{\text{DD}} = 150\text{V}$
$t_r$	Rise Time	—	7.2	—	ns	$I_D = 0.96\text{A}$
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	23	—		$R_G = 2.2\Omega$
$t_f$	Fall Time	—	23	—		$V_{\text{GS}} = 10\text{V}$ ③
$C_{\text{iss}}$	Input Capacitance	—	730	—		$V_{\text{GS}} = 0\text{V}$
$C_{\text{oss}}$	Output Capacitance	—	100	—	pF	$V_{\text{DS}} = 25\text{V}$
$C_{\text{rss}}$	Reverse Transfer Capacitance	—	20	—		$f = 1.0\text{MHz}$
$C_{\text{oss}}$	Output Capacitance	—	940	—		$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 1.0\text{V}, f = 1.0\text{MHz}$
$C_{\text{oss}}$	Output Capacitance	—	39	—		$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 240\text{V}, f = 1.0\text{MHz}$
$C_{\text{oss eff.}}$	Effective Output Capacitance	—	87	—		$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V to } 240\text{V}$ ③

## Avalanche Characteristics

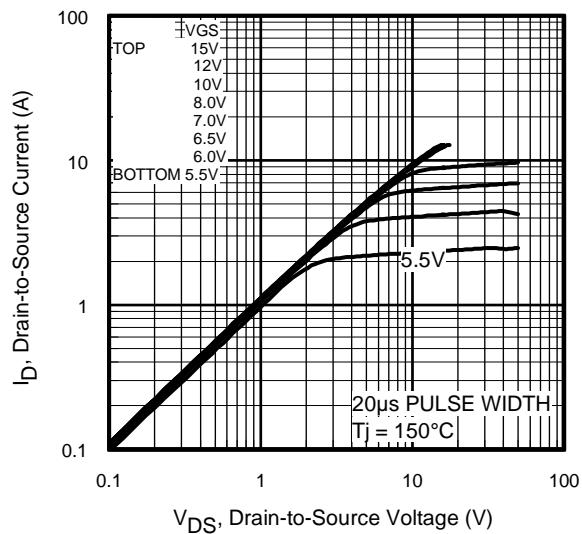
	Parameter	Typ.	Max.	Units
$E_{\text{AS}}$	Single Pulse Avalanche Energy ②	—	47	mJ
$I_{\text{AR}}$	Avalanche Current ①	—	1.9	A

## Diode Characteristics

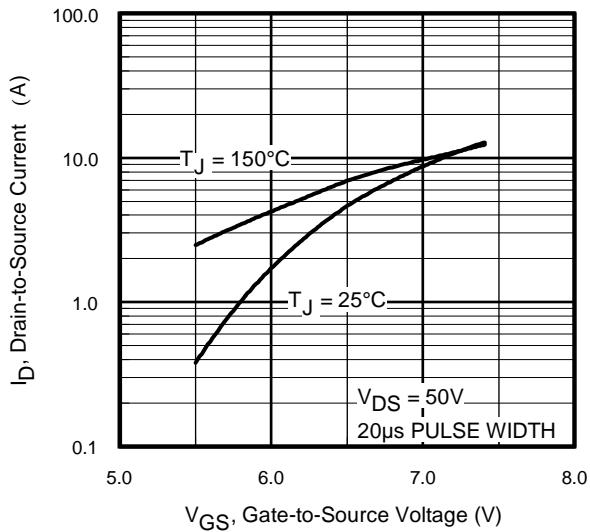
	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_s$	Continuous Source Current (Body Diode)	—	—	1.6	A	MOSFET symbol showing the integral reverse p-n junction diode.
$I_{\text{SM}}$	Pulsed Source Current (Body Diode) ①	—	—	13		
$V_{\text{SD}}$	Diode Forward Voltage	—	—	1.5	V	$T_J = 25^\circ\text{C}, I_S = 0.96\text{A}, V_{\text{GS}} = 0\text{V}$ ③
$t_{\text{rr}}$	Reverse Recovery Time	—	86	130	ns	$T_J = 25^\circ\text{C}, I_F = 0.96\text{A}$
$Q_{\text{rr}}$	Reverse Recovery Charge	—	250	380	nC	$dI/dt = 100\text{A}/\mu\text{s}$ ③



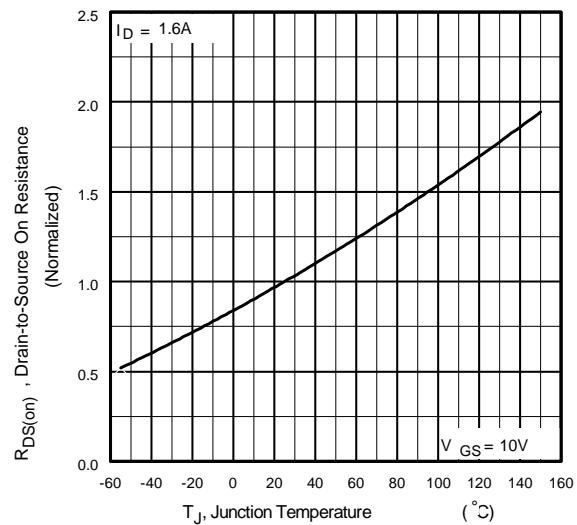
**Fig 1.** Typical Output Characteristics



**Fig 2.** Typical Output Characteristics



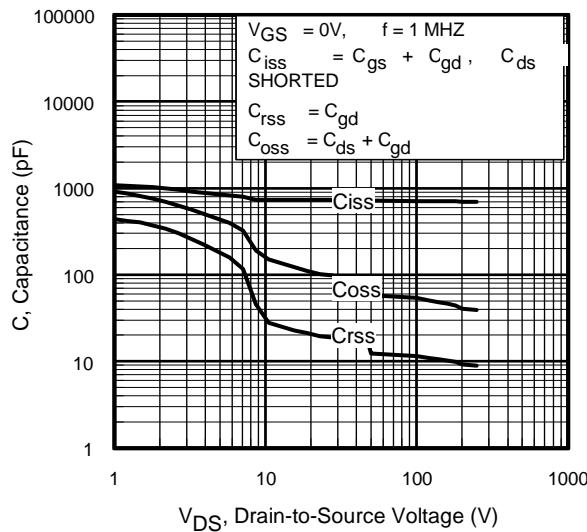
**Fig 3.** Typical Transfer Characteristics



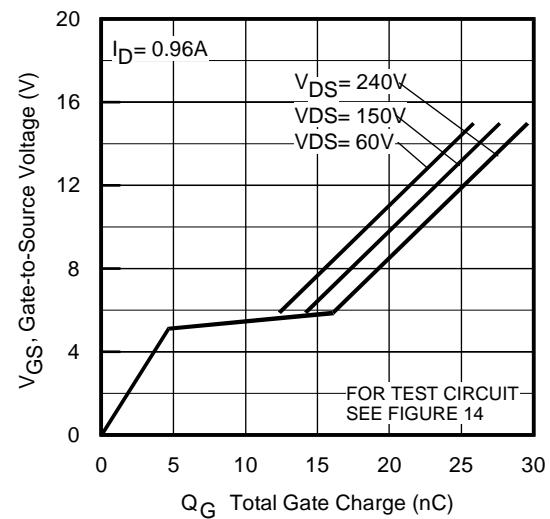
**Fig 4.** Normalized On-Resistance  
Vs. Temperature

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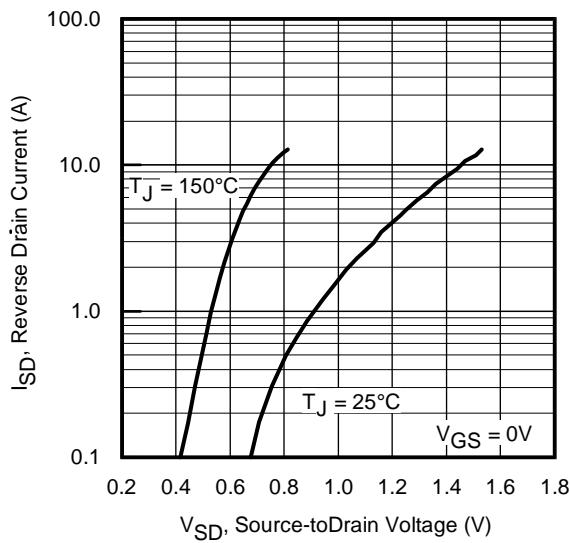
International  
**IR** Rectifier



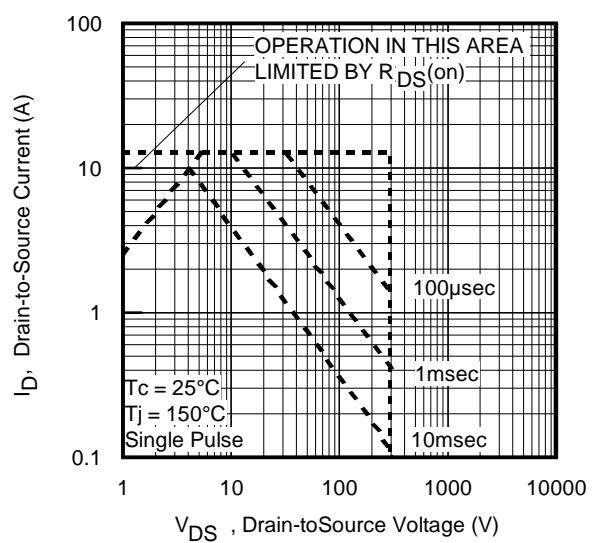
**Fig 5.** Typical Capacitance Vs.  
Drain-to-Source Voltage



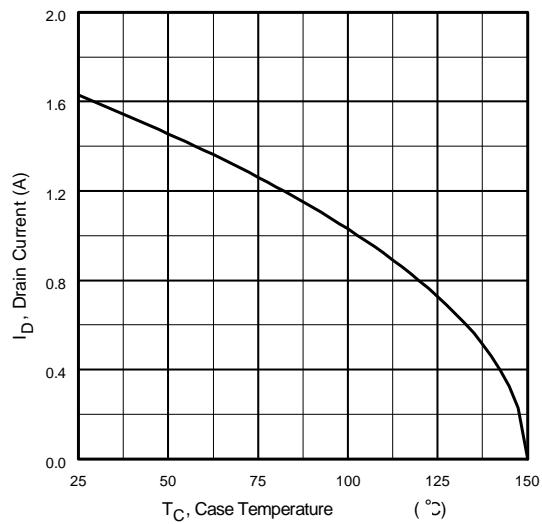
**Fig 6.** Typical Gate Charge Vs.  
Gate-to-Source Voltage



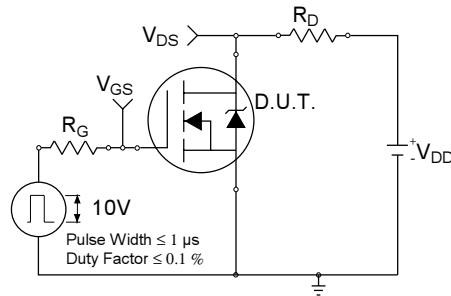
**Fig 7.** Typical Source-Drain Diode  
Forward Voltage



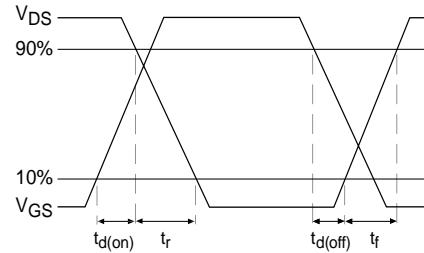
**Fig 8.** Maximum Safe Operating Area



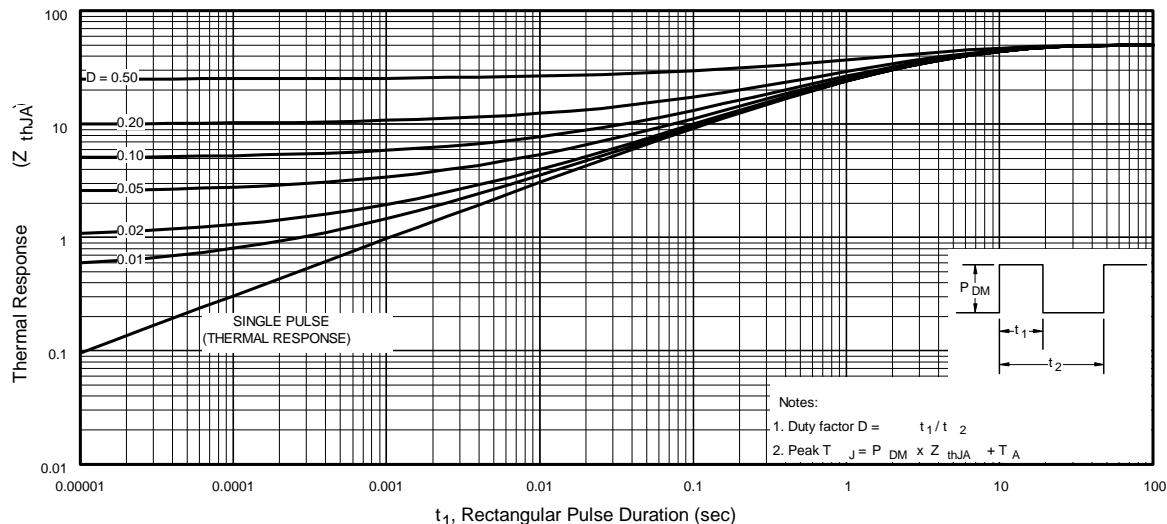
**Fig 9.** Maximum Drain Current Vs.  
Ambient Temperature



**Fig 10a.** Switching Time Test Circuit



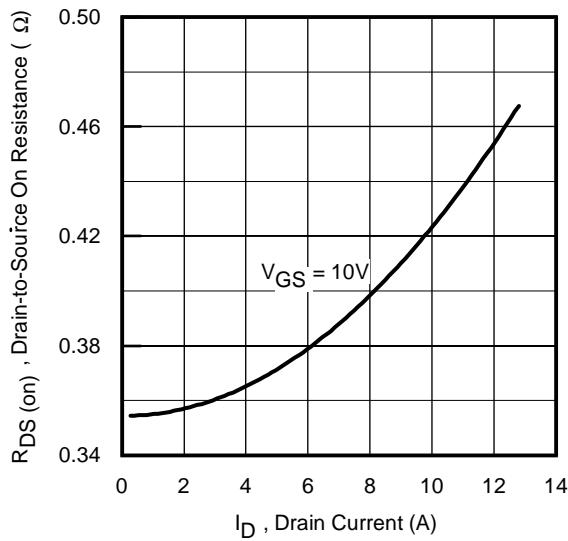
**Fig 10b.** Switching Time Waveforms



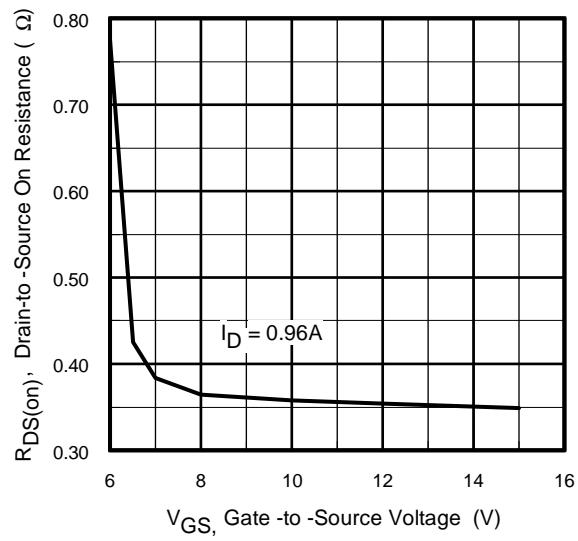
**Fig 11.** Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

# IRF3000

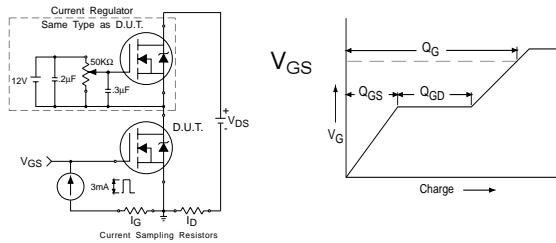
International  
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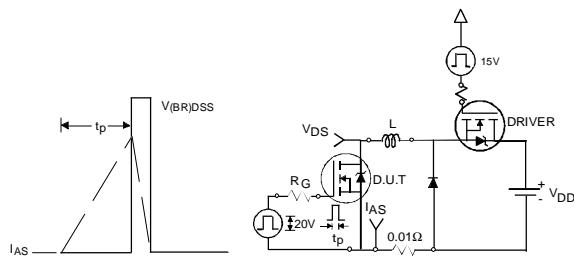
**Fig 12.** On-Resistance Vs. Drain Current



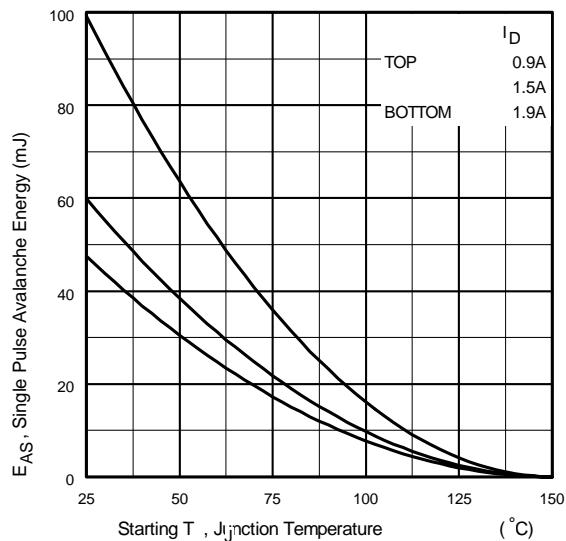
**Fig 13.** On-Resistance Vs. Gate Voltage



**Fig 14a&b.** Basic Gate Charge Test Circuit and Waveform

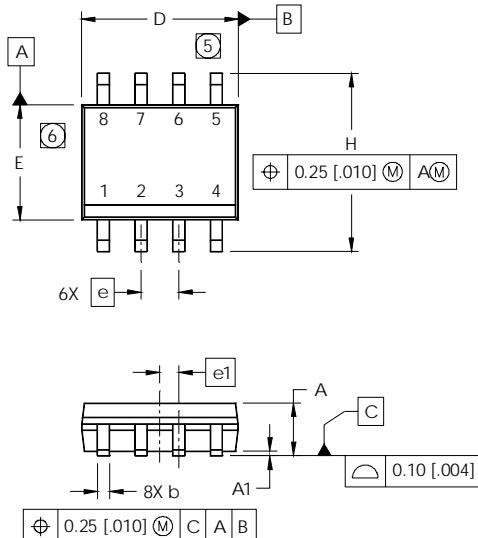


**Fig 15a&b.** Unclamped Inductive Test circuit and Waveforms

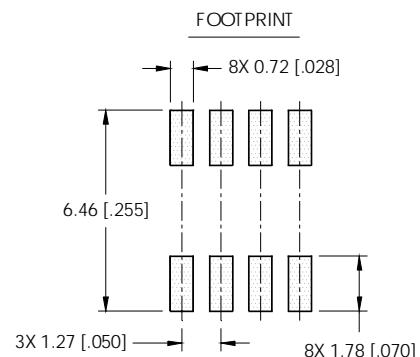
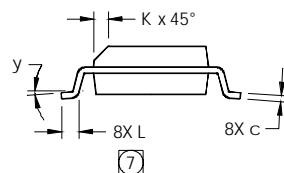


**Fig 15c.** Maximum Avalanche Energy Vs. Drain Current

## SO-8 Package Details

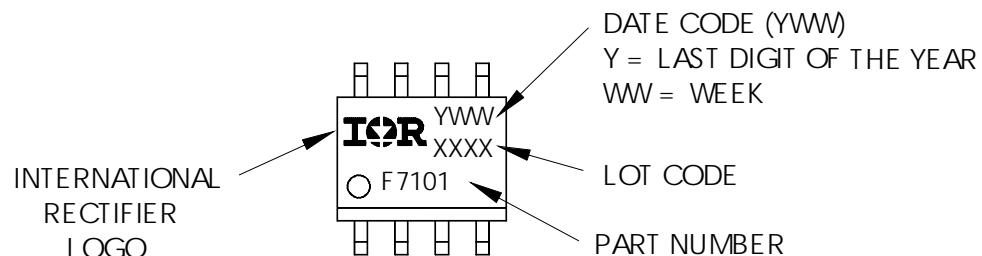


DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
b	.013	.020	0.33	0.51
c	.0075	.0098	0.19	0.25
D	.189	.1968	4.80	5.00
E	.1497	.1574	3.80	4.00
e	.050	BASIC	1.27	BASIC
e1	.025	BASIC	0.635	BASIC
H	.2284	.2440	5.80	6.20
K	.0099	.0196	0.25	0.50
L	.016	.050	0.40	1.27
y	0°	8°	0°	8°



## SO-8 Part Marking

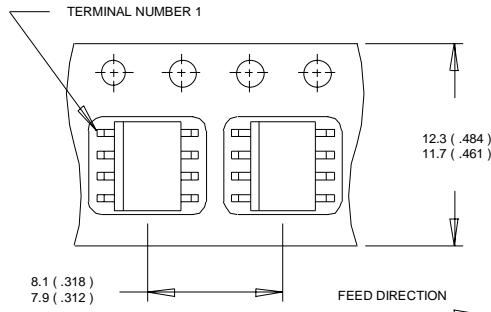
EXAMPLE: THIS IS AN IRF7101 (MOSFET)



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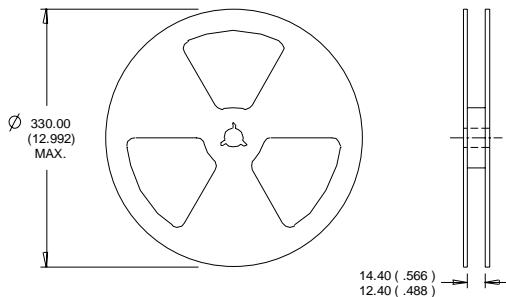
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## SO-8 Tape and Reel



NOTES:

1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES :

1. CONTROLLING DIMENSION : MILLIMETER.
2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

**Notes:**

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting  $T_J = 25^\circ\text{C}$ ,  $L = 26\text{mH}$   
 $R_G = 25\Omega$ ,  $I_{AS} = 1.9\text{A}$ .
- ③ Pulse width  $\leq 300\mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- ④ When mounted on 1 inch square copper board
- ⑤  $C_{oss}$  eff. is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$
- ⑥  $I_{SD} \leq 0.96\text{A}$ ,  $di/dt \leq 170\text{A}/\mu\text{s}$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  $T_J \leq 150^\circ\text{C}$

Data and specifications subject to change without notice.  
This product has been designed and qualified for the Industrial market.  
Qualification Standards can be found on IR's Web site.

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